

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination KIM, HAHKKYU	
		Examiner Chen-Wen Jiang	Art Unit 3744	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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FOREIGN PATENT DOCUMENTS

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	N	JP 08159617 A	06-1996	Japan	YABU et al.	F25B 41/06
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